Serial No.

U.S. Depar	tment o	f Commerce, Pate	ent and Tradem	nark Office	Docket N	0.	Serial No.
(PTO Form	1449 n	nodified)		63P1/DISP DWR/RKK	10/321,289		
LIST OF P	ATENT	S AND PUBLICA	TIONS CITED	BY APPLICANT	Applicant Kim, et al		Confirmation No.: 2911
(Use sever	al sheet	s if necessary)			Filing Dat	е	Group
	ı	Examiner	FEB 0 3 2	1004 빙	Decembe	r 17, 2002	3742
U.S. Paten	t Docui	ments	FEE				
*Examiner Initial		Document Number	Issue BADEN Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
	A1	4,486,487	12/04/84	Skarp	428	216	04/25/1983
	A2	4,767,494	08/30/88	Kobayashi et al.	156	606	09/19/1986
"	A3	4,806,321	02/21/89	Nishizawa et al.	422	245	07/21/1985
	A4	4,813,846	03/21/89	Helms	414	744.1	04/29/87
· · · · · · · · · · · · · · · · · · ·	A5	4,829,022	05/09/89	Kobayashi et al.	437	107	12/09/1986
	A6	4,838,983	06/13/89	Schumaker et al.	156	613	03/18/1988
	A7	4,838,993	06/13/89	Aoki et al.	156	643	12/03/1987
	A8	4,840,921	06/20/89	Matsumoto	437	89	06/30/1988
	A9	4,845,049	07/04/89	Sunakawa	437	81	03/28/1988
	A10	4,859,625	08/22/89	Nishizawa et al.	437	81	11/20/1987
	A11	4,859,627	08/22/89	Sunakawa	437	81	07/01/1988
	A12	4,861,417	08/29/89	Mochizuki et al.	156	610	03/24/1988
	A13	4,876,218	10/24/89	Pessa et al.	437	107	09/26/1988
	A14	4,917,556	04/17/90	Stark et al.	414	217	05/26/89
	A15	4,927,670	05/22/1990	Erbil	427	255.3	06/22/1988
-	A16	4,931,132	06/05/90	Aspnes et al.	156	601	10/07/1988
	A17	4,951,601	08/28/90	Maydan, et al.	118	719	06/23/89
	A18	4,960,720	10/02/90	Shimbo	437	105	08/24/1987
	A19	4,975,252	12/04/90	Nishizawa et al.	422	245	05/26/1989
	A20	5,000,113	03/19/91	Wang et al.	118	723	12/19/86
***************************************	A21	5,013,683	05/07/91	Petroff et al.	437	110	01/23/1989
	A22	5,028,565	07/02/1991	Chang, et al.	437	192	08/25/1989
	A23	5,082,798	01/21/92	Arimoto	437	108	09/27/1990
1, 10, 10, 10, 10, 10, 10, 10, 10, 10, 1	A24	5,085,885	02/04/92	Foley et al.	477	38	09/10/1990
	A25	5,091,320	02/25/92	Aspnes et al.	437	8	06/15/1990
	A26	5,130,269	07/14/92	Kitahara et al.	437	111	04/25/1989
	A27	5,166,092	11/24/92	Mochizuki et al.	437	105	10/30/1990
	A28	5,173,474	12/22/1992	Connell, et al.	. 505	1	03/11/1991
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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U.S. Depar	tment o	f Commerce, Pa	tent and Tradem	ark Office	Docket I	No.	Serial No.
(PTO Form	1449 n	nodified)		163P1/DISP RDWR/RKK	10/321,289		
LIST OF P	ATENT	S AND PUBLICA	ATIONS CITED I	BY APPLICANT	Applicar Kim, et a		Confirmation No.: 2911
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*Examiner Initial		Document Number	Issue RADEM	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
***	A29	5,186,718	02/16/93	Tepman et al.	29	25.01	04/15/91
	A30	5,205,077	04/27/93	Wittstock	51	165 R	08/28/91
	A31	5,234,561	08/10/93	Randhawa et al.	204	192.38	08/25/88
	A32	5,246,536	09/21/93	Nishizawa et al.	156	610	03/10/1989
	A33	5,250,148	10/05/93	Nishizawa et al.	156	611	11/12/1991
	A34	5,254,207	10/19/93	Nishizawa et al.	156	601	11/30/1992
	A35	5,256,244	10/26/93	Ackerman	156	613	02/10/1992
	A36	5,259,881	11/09/93	Edwards, et al.	118	719	05/17/91
	A37	5,270,247	12/14/93	Sakuma et al.	437	133	07/08/1992
-	A38	5,278,435	01/11/94	Van Hove et al.	257	184	06/08/1992
-	A39	5,286,296	02/15/94	Sato et al.	118	719	01/09/92
	A40	5,290,748	03/01/94	Knuuttila et al.	502	228	07/16/1992
—	A41	5,296,403	03/22/94 .	Nishizawa et al.,	437	133	10/23/1992
	A42	5,300,186	04/05/94	Kitahara et al.	156	613	04/07/1992
	A43	5,311,055	05/10/94	Goodman et al.	257	593	11/22/1991
	A44	5,316,615	05/31/94	Copel	117	95	03/09/1993
	A45	5,316,793	05/31/94	Wallace et al.	427	248.1	07/27/1992
	A46	5,330,610	07/19/94	Eres et al.	117	86	05/28/1993
	A47	5,336,324	08/09/94	Stall et al.	118	719	12/04/1991
	A48	5,338,389	08/16/94	Nishizawa et al.	117	89	04/21/1993
	A49	5,348,911	09/20/94	Jurgensen et al.	117	91	04/26/1993
	Ą50	5,395,791	03/07/95	Cheng et al.	437	105	10/20/1993
	A51	5,438,952	08/08/1995	Otsuka	117	84	01/31/1994
	A52	5,439,876	08/08/95	Graf et al.	505	447	08/16/1993
	A53	5,443,033	08/22/95	Nishizawa et al.	117	86	03/11/1994
	A54	5,455,072	10/03/95	Bension et al.	427	255.7	11/18/1992
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U.S. Depar	tment o	f Commerce, Pat	ent and Tradem	ark Office	Docket N	lo.	Serial No.
(PTO Form	1449 m	nodified)				163P1/DISP RDWR/RKK	
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*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
	A55	5,458,084	10/17/95	Thorne et al.	117	89	12/09/1993
	A56	5,469,806	11/28/95	Mochizuki et al.	117	97	08/20/1993
	A57	5,484,664	01/16/96	Kitahara et al.	428	641	01/21/1994
	A58	5,521,126	05/28/96	Okamura et al.	437	235	06/22/1994
	A59	5,527,733	06/18/96	Nishizawa et al.	437	160	02/18/1994
	A60	5,532,511	07/02/96	Nishizawa et al.	257	627	03/23/1995
	A61	5,540,783	07/30/96	Eres et al.	118	725	05/26/1994
	A62	5,561,735	10/01/1996	Camm	392	416	08/30/1994
	A63	5,580,380	12/03/1996	Liu, et al.	117	86	01/30/1995
	A64	5,601,651	02/11/97	Watabe	118	715	12/14/1994
**	A65	5,609,689	03/11/97	Kato et al.	118	719	06/03/96
	A66	5,616,181	04/01/97	Yamamoto et al.	118	723 ER	11/21/1995
	A67	5,637,530	06/10/97	Gaines et al.	114	105	06/10/1996
	A68	5,641,984	06/24/97	Aftergut et al.	257	433	08/19/1994
	A69	5,644,128	07/01/97	Wollnik et al.	250	251	08/25/1994
	A70	5,667,592	09/16/97	Boitnott et al.	118	719	04/16/96
	A71	5,693,139	12/02/97	Nishizawa et al.	117	89	06/15/1993
	A72	5,695,564	12/09/97	Imahashi	118	719	08/03/95
	A73	5,705,224	01/06/98	Murota et al.	427	248.1	01/31/1995
	A74	5,707,880	01/13/98	Aftergut et al.	437	3	01/17/1997
	A75	5,730,801	03/24/98	Tepman et al.	118	719	08/23/94
	A76	5,730,802	03/24/98	Ishizumi et al.	118	719	12/27/1996
	A77	5,747,113	05/05/98	Tsai	427	255.5	07/29/1996
	A78	5,749,974	05/12/98	Habuka et al.	118	725	07/13/1995
	A79	5,788,447	08/04/98	Yonemitsu et al.	414	217	08/05/96
	A80	5,788,799	08/04/98	Steger, et al.	156	345	06/11/96
Examiner	-				Date Cor	nsidered	

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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U.S. Depar	tment of	Commerce, Pate	nt and Tradema	ark Office	Docket N	0.	Serial No.
(PTO Form	1449 m	odified)		63P1/DISP DWR/RKK	10/321,289		
LIST OF PA	ATENTS	AND PUBLICAT	ONS CITED B	Y APPLICANT	Applicant Kim, et al	l.	Confirmation No.: 2911
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*Examiner Initial		Document Number	Issue BADEMA Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
	A81	5,801,634	09/01/98	Young et al.	340	635	09/08/97
	A82	5,830,270	11/03/98	McKee et al.	117	106	08/05/1996
	A83	5,850,071	12/15/1998	Makiguchi, et al.	219	390	08/09/1996
	A84	5,851,849	12/22/98	Comizzoli et al.	438	38	05/22/1997
	A85	5,855,675	01/05/99	Doering et al.	118	719	03/03/1997
	A86	5,856,219	01/05/99	Naito et al.	438	241	08/18/97
	A87	5,858,102	01/12/99	Tsai	118	719	02/14/1998
	A88	5,866,213	02/02/99	Foster et al.	427	573	07/19/97
	A89	5,866,795	02/02/99	Wang et al.	73	1.36	03/17/97
	A90	5,882,165	03/16/99	Maydan et al.	414	217	09/10/97
	A91	5,882,413	03/16/99	Beaulieu et al.	118	719	07/11/97
	A92	5,904,565	05/18/1999	Nguyen, et al.	438	687	07/17/1997
.,,	A93	5,923,056	07/13/99	Lee et al.	257	192	03/12/1998
	A94	5,923,985	07/13/99	Aoki et al.	438	301	01/14/1997
	A95	5,925,574	07/20/99	Aoki et al.	437	31	04/10/1992
	A96	5,928,389	07/27/99	Jevtic	29	25.01	10/21/96
	A97	5,942,040	08/24/99	Kim et al.	118	726	08/27/1997
	A98	5,947,710	09/07/1999	Cooper, et al.	418	63	06/16/1997
	A99	5,972,430	10/26/99	DiMeo, Jr. et al.	427	255.32	11/26/1997
	A100	6,001,669	12/14/99	Gaines et al.	438	102	07/21/1992
<del></del>	A101	6,025,627	02/15/00	Forbes et al.	257	321	05/29/1998
	A102	6,036,773	03/14/00	Wang et al.	117	97	03/27/1997
	A103	6,043,177	03/28/00	Falconer et al.	502	4	01/21/1997
	A104	6,046,439	04/04/2000	Johnsgard, et al.	219	444.1	06/16/1997
	A105	6,051,286	04/18/00	Zhao et al.	427	576	08/22/97
	A106	6,062,798	05/16/00	Muka	414	416	06/13/96
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U.S. Depar	tment of	Commerce, Pater	nt and Tradem	ark Office	Docket	t No.		Serial No.
(PTO Form							P1/DISP /R/RKK	10/321,289
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*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Cla s	as Si	ubclass	Filing Date If Appropriate
<del></del>	A107	6,071,808	06/06/00	Merchant et al.	43	8 6	33	06/23/99
	A108	6,084,302	07/04/00	Sandhu	25	7 7	51	12/26/95
	A109	6,086,677	07/11/00	Umotoy et al.	11	8 7	15	06/16/98
	A110	6,110,556	08/29/00	Bang, et al.	42	8 64	4.1	10/17/97
	A111	6,113,977	09/05/00	Soininen et al.	42	7 64	4	09/11/1997
	A112	6,117,244	09/12/00	Bang, et al.	11	8 7	15	03/24/98
	A113	6,124,158	09/26/00	Dautartas et al.	43	8 2	16	06/08/1999
	A114	6,130,147	10/10/00	Major et al.	43	8 60	04	03/18/1997
	+	6,140,237	10/31/00	Chan et al.	43	8 6	87	04/19/99
	A116	6,140,238	10/31/00	Kitch	43	88 68	87	04/21/99
	A117	6,143,659	11/07/00	Leem	43	8 6	88	08/27/98
	A118	6,144,060	11/07/00	Park et al.	25	7 3	10	07/31/98
	A119	6,147,334	11/14/2000	Hannigan	21	9 5	44	01/29/1999
	A120	6,151,447	11/21/2000	Moore, et al.	39	2 4	18	11/25/1997
	A121	6,158,446	12/12/00	Mohindra et al.	13	34 2	5.4	09/04/98
	A122	6,174,809	01/16/2001	Kang, et al.	43	88 6	82	12/15/1998
		6,203,613	03/20/2001	Gates, et al.	11	7 10	04	10/19/1999
	A124	6,206,967	03/27/01	Mak, et al.	11	8 6	66	06/14/00
	A125	6,207,302	03/27/2001	Sugiura, et al.	42	28 69	90	03/02/1998
		6,248,605	06/19/2001	Harkonen, et al.	43	8 2	9	06/02/1999
	A127		08/07/01	Kao et al.	43	88 7	27	10/13/99
	A128	6,287,965	09/11/2001	Kang, et al.	43	88 6	48	02/23/2000
	A129	6,291,876	09/18/2001	Stumborg, et al.	25	57 6	32	08/20/1998
	A130		11/13/2001	Yitzchaik, et al.	42	28 3	39	03/23/1999
	A131	2001/0031562	10/18/2001	Raaijmakers, et a	al. 43	88 7	70	02/22/2001
	A132	2001/0034123	10/25/2001	Jeon, et al.	43	88 6	43	04/06/2001
$\overline{}$	A133	2001/0041250	11/15/01	Werkhoven et al.	42	28 2	12	03/06/01
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

Sheet 6 of 15 sheet(s) U.S. Department of Commerce, Patent and Trademark Office Docket No. Serial No. AMAT/5163P1/DISP 10/321,289 (PTO Form 1449 modified) LAY/AHRDWR/RKK LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT Confirmation No.: **Applicant** 2911 Kim, et al. Group Filing Date (Use several sheets if necessary) FEB 0 3 2004 3742 December 17, 2002 Examiner **Foreign Patent Documents** Date BADEN Country **Translation** Class Subclass \*Examiner Document Initial Number YES NO  $\boxtimes$ 01/09/1997 DE H01L 21/283 196 27 017 **B1**  $\boxtimes$ DE H01L 21/3205 07/01/1999 **B2** 198 20 147  $\boxtimes$ EP H01L 39/24 12/06/1989 **B3** 0 344 352 A1 EP G03F 7/36 0 429 270 A2 05/29/1991 **B4**  $\boxtimes$ EP C30B 25/02 0 442 490 A1 08/21/1991 **B5**  $\boxtimes$ 0 799 641 A2 10/08/1997 20/32 EP B01J **B6**  $\boxtimes$ 39/24 FR H01L **B7** 2 626 110 07/21/1989  $\boxtimes$ 2 692 597 12/24/1993 FR C23C 16/00 **B8** GB H01L 21/00 2 298 314 A 08/28/1996 **B9** GB C23C 16/44 05/02/12001 **B10** 2 355 727A  $\boxtimes$ ∕B11 JP 21/20 06/15/1983 H01L 58-100419 JP C01B 33/113 60-065712 A 04/15/1985 **B12**  $\boxtimes$ JP **B01J** 19/08 02/20/1986 61-035847 B13  $\boxtimes$ 21/205 JP H01L 09/18/1986 61-210623 **B14**  $\boxtimes$ JP H01L 21/203 03/30/1987 **B15** 62-069508 **B**16  $\boxtimes$ 25/02 JP C30B 62-091495 A 04/25/1987  $\boxtimes$ H01L JP 21/203 **B17** 62-141717 06/25/1987  $\boxtimes$ JP **C30B** 29/40 62-167297 07/23/1987 **B18**  $\boxtimes$ C30B JP 29/40 07/28/1987 **B19** 62-171999 JP H01L 21/205 **B20** 62-232919 10/13/1987  $\boxtimes$ JP H01L 21/203 63-062313 03/18/1988 **B21**  $\boxtimes$ 04/15/1988 JP C30B 21/40 **B22** 63-085098 H01L 21/365  $\boxtimes$ 04/21/1988 63-090833 **B23** JP  $\boxtimes$ **B24** 63-222420 JP H01L 21/205 09/16/1988  $\boxtimes$ JP H01L 21/205 **B25** 63-222421 09/16/1988  $\boxtimes$ 21/205 63-227007 09/21/1988 JP H01L **B26**  $\boxtimes$ 21/205 63-252420 H01L 10/19/1988 JP **B27**  $\boxtimes$ 21/205 JP H01L 63-266814 11/02/1988 **B28** Examiner **Date Considered** 

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/	B29	64-009895	01/13/1989	JP	C30B	29/40	$\boxtimes$	
	B30	64-009896	01/13/1989	JP	C30B	29/40	$\boxtimes$	
	B31	64-009897	01/13/1989	JP	C30B	29/40	$\boxtimes$	
	B32	64-037832	02/08/1989	JP	H01L	21/205	$\boxtimes$	
	B33	64-082615	03/28/1989	JP	H01L	21/205	$\boxtimes$	
_	B34	64-082617	03/28/1989	JP	H01L	21/205	$\boxtimes$	
	B35	64-082671	03/28/1989	JP	H01L	29/78	$\boxtimes$	
<u>.</u>	B36	64-082676	03/28/1989	JP	H01L	29/80	$\boxtimes$	
	B37	64-090524	04/07/1989	JP	H01L	21/205	$\boxtimes$	
	B38	01-103982	04/21/1989	JP	C30B	23/08	$\boxtimes$	
	B39	01-103996	04/21/1989	JP	C30B	29/40	$\boxtimes$	
-	B40	01-117017	05/09/1989	JP	H01L	21/203	$\boxtimes$	
	B41	01-143221	06/05/1989	JP	H01L	21/314	$\boxtimes$	
	B42	01-143233	06/05/1989	JP	H01L	21/76	$\boxtimes$	
/	B43	01-154511	06/16/1989	JP	H01L	21/20	$\boxtimes$	
	B44	01-236657	09/21/1989	JP	H01L	29/80	$\boxtimes$	
	B45	01-245512	09/29/1989	JP	H01L	21/205	$\boxtimes$	
	B46	01-264218	10/20/1989	JP	H01L	21/205	$\boxtimes$	
V	B47	01-270593	10/27/1989	JP	C30B	25/02	$\boxtimes$	
	B48	01-272108	10/31/1989	JP	H01L	21/203	$\boxtimes$	
	B49	01-290221	11/22/1989	JP	H01L	21/205	$\boxtimes$	
"	B50	01-290222	11/22/1989	JP	H01L	21/205	$\boxtimes$	
*****	B51	01-296673	11/30/1989	JP	H01L	29/88	$\boxtimes$	
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	B55	02-012814	01/17/1990	JP	H01L	21/205	$\boxtimes$	
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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	B56	02-014513	01/18/1990	JP	H01L	21/205	$\boxtimes$	
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	B111	05-186295	07/27/1993	JP	C30B	25/02	$\overline{\boxtimes}$	
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-	B137	11-269652	10/05/1999	JP	C23C	16/44	$\boxtimes$	
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	B144	2000-340883	12/08/2000	JP	H01S	5/125	$\boxtimes$	
····	B145	2000-353666	12/19/2000	JP	H01L	21/205	$\boxtimes$	
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	B147	2001-172767	06/26/2001	JP	C23C	16/40	$\boxtimes$	
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	B150	2001-220287	08/14/2001	JP	C30B	25/02	$\boxtimes$	
	B151	2001-220294	08/14/2001	JP	C30B	29/20	$\boxtimes$	
	B152	2001-240972	09/04/2001	JP	C23C	16/458		
	B153	2001-254181	09/18/2001	JP	C23C	16/46		$\boxtimes$
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	B168	00/15865 A1	03/23/2000	WO	C23C	16/00		$\boxtimes$
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	B171	00/63957 A1	10/26/2000	wo	H01L	21/205		$\boxtimes$
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	C2		ayer Deposition of SiO <sub>2</sub> Using Cataly view & Letters, 6(3&4) (1999), pp. 4		miting Surface
	C3	_	mic-layer chemical-vapor-deposition i., Vol. 130-132 (1998), pp. 202-207		extremely low hydrogen
	C4	George, et al., "Surface	Chemistry for Atomic Layer Growth	n, J. Phys. Chem., Vol. 100 (	(1996), pp. 13121-131.
	C5/		ic layer controlled deposition of \$ , <i>Appl. Surf. Sci.</i> , Vol. 82/83 (199		Bbinary reaction
	C6	Wise, et al., "Diethylo Symp. Proc., Vol. 33	liethoxysilane as a new precurso 4 (1994), pp. 37-43.	or for SiO <sub>2</sub> growth on silico	on", Mat. Res. Soc.
	C7		nesis of oxide thin films and overl ci. & Eng., Vol. B41 (1996), pp. 2	• •	taxy for advanced
	C8		y conformal TiN and Al <sub>2</sub> O <sub>3</sub> films ol. 5(1) (January 1999), pp. 7-9.	deposited by atomic layer	deposition", Chemic
	C9		ally controlled growth of tungster Sci., Vol 162-163 (2000), pp. 4		ng sequential surface
	C10	NH/sub3/", Symp.: Ac	yer deposition of TiN thin films be dvanced Interconnects and Contagr. 13-16, 1998), pp. 337-342.		
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	C13	Martensson, et al., "A (Feb. 1, 1997), pp. 45	Atomic Layer Epitaxy of Copper of 5-50.	on Tantalum", <i>Chemical V</i>	apor Deposition, 3(1)
	C14	Ritala, et al. "Atomic 1995), pp. 2731-737.	Layer Epitaxy Growth of TiN Thi	n Films", J. Electrochem.	Soc., 142(8) (Aug.
	C15	Elers, et al., "NbC15 468-474.	as a precursor in atomic layer ep	oitaxy", Appl. Surf. Sci., V	ol. 82/83 (1994), pp.
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	C21	Elam, et al., "Nucleation and growth during tungsten atomic layer deposition on SiO2 surfaces," Thin Solid Films 386 (2001) Pages 41 – 52, (Accepted Dec. 14, 2000).				
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	C24	Suzuki, et al., "A 0.2-µm contact filing by 450°C-h resistivity", IEDM 92-979, pp. 11.8.1 – 11.8.3	0.2-µm contact filing by 450°C-hydrazine-reduced TiN film with low 192-979, pp. 11.8.1 – 11.8.3			
	C25	Suzuki, et al., "LPCVD-TiN Using Hydrazine and TiCl <sub>4</sub> ", VMIC Conference (June 8-9, 1993), pp. 418-423				
	C26	IBM Tech. Disc. Bull. "Knowledge-Based Dynamic Scheduler in Distributed Computer Control, (June 1990), pp. 80-84				
	C27	IBM Tech. Disc. Bull. "Multiprocessor and Multitasking Architecture for Tool Control of the Advanced via Inspection Tools" (May 1992), pp. 190-191				
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	C30	NERAC.COM Retro Search: Atomic Layer Deposition of Copper, dated October 11, 2001				
	C31	NERAC.COM Retro Search: Atomic Layer Deposition / Epitaxy Aluminum Oxide Plasma, dated October 2, 2001				
	C32	NERAC Search abstract of "Atomic Layer deposition of Ta and Ti for Interconnect Diffusion Barriers", by Rossnagel, et al., J. Vac. Sci. & Tech., 18(4) (July 2000)				
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	C34	Abstracts of search results re atomic layer deposition, search dated January 24, 2002				
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	C36	Abstracts of articles re atomic layer deposition and semiconductors and copper				
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